DfRSoft Example 1 High Temperature Accelerated life Test

Here we will use the traditional Arrhenius model with a conservative estimate for the activation energy parameter in the model as a basis of providing an acceleration factor estimate. The model is described by $A_T = Exp[(E_a / K_B)^*(1/T_{stress} - 1/T_{use})]$

Notation:

 T_{stress} =Test Temperature (°K) T_{use} =nominal use temperature (°K) E_a =activation energy: 0.7 eV K_B = 8.616x10⁻⁵ eV/°K (Boltzmann's constant)

$$A_{T} = Exp\left\{\frac{E_{a}}{K_{B}}\left[\frac{1}{T_{Use}} - \frac{1}{T_{Stress}}\right]\right\}$$

$$Ln(t_{f}) = C + \frac{E_{a}}{K_{B}T}$$
Notation

$$A_{T}=\text{Temperature acceleration factor}$$

$$T_{\text{stress}}=\text{Test temperature (°K)}$$

$$T_{\text{use}}=\text{Use temperature (°K)}$$

$$E_{a}=\text{Activation energy}$$

$$t_{f}= 8.6173 \times 10^{-5} \text{eV/°K} (\text{Boltzmann's})$$

$$C=\text{constant}$$

EXAMPLE: Using the HTOL Model

Estimate the test time to simulate 10 years of life in an HTOL test. The activation energies for the potential failure modes are unknown. Therefore, assume a conservative value of 0.7 eV for the activation energy. The device junction temperature rise is measured to be 15°C above ambient. The test temperature is +110°C and the nominal use temperature is +40°C.

SOLUTION: Since the junction temperature rise is 15°C, then the actual use and test temperatures are $T_{use}=15^{\circ}C + 40^{\circ}C = +55^{\circ}C$ $T_{Stress}=15^{\circ}C + 110^{\circ}C = +125^{\circ}C$ From Figure 9.2, the acceleration factor is $A_{T} = Exp \{(0.7 \text{ eV}/8.6173 \text{ x}10^{-5} \text{ eV}/^{\circ}\text{K}) \times [1/(273.15+55) - 1/(273.15+125)^{\circ}\text{K}]\} = 77.6$ From Equation 9.1, the test time to simulate 10 years of life (87,600 hours) is Test Time=Life Time/A_T=87600/77.6=1,129 hours



